



# RF Power Field Effect Transistor

## N-Channel Enhancement-Mode Lateral MOSFET

Designed for N-CDMA base station applications with frequencies from 869 to 960 MHz. Suitable for multicarrier amplifier applications.

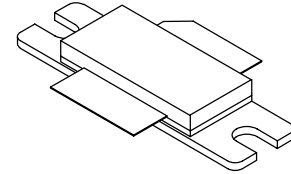
- Typical Single-Carrier N-CDMA Performance @ 880 MHz:  $V_{DD} = 28$  Volts,  $I_{DQ} = 1500$  mA,  $P_{out} = 33$  Watts Avg., IS-95 CDMA (Pilot, Sync, Paging, Traffic Codes 8 Through 13). Channel Bandwidth = 1.2288 MHz. PAR = 9.8 dB @ 0.01% Probability on CCDF.  
Power Gain — 19.7 dB  
Drain Efficiency — 28.4%  
ACPR @ 750 kHz Offset — -46.8 dBc in 30 kHz Bandwidth
- Capable of Handling 10:1 VSWR, @ 28 Vdc, 880 MHz, 150 Watts CW Output Power

### Features

- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Internally Matched for Ease of Use
- Qualified Up to a Maximum of 32  $V_{DD}$  Operation
- Integrated ESD Protection
- Lower Thermal Resistance Package
- Low Gold Plating Thickness on Leads, 40 $\mu$ ” Nominal.
- RoHS Compliant
- In Tape and Reel. R3 Suffix = 250 Units per 56 mm, 13 inch Reel.

**MRF5S9150HR3**

**880 MHz, 33 W AVG., 28 V  
SINGLE N-CDMA  
LATERAL N-CHANNEL  
RF POWER MOSFET**



**CASE 465-06, STYLE 1  
NI-780**

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**Table 1. Maximum Ratings**

| Rating                         | Symbol    | Value       | Unit        |
|--------------------------------|-----------|-------------|-------------|
| Drain-Source Voltage           | $V_{DSS}$ | -0.5, +68   | Vdc         |
| Gate-Source Voltage            | $V_{GS}$  | -0.5, +15   | Vdc         |
| Storage Temperature Range      | $T_{stg}$ | -65 to +150 | $^{\circ}C$ |
| Case Operating Temperature     | $T_C$     | 150         | $^{\circ}C$ |
| Operating Junction Temperature | $T_J$     | 200         | $^{\circ}C$ |

**Table 2. Thermal Characteristics**

| Characteristic  | Symbol          | Value (1)    | Unit          |
|---|-----------------|--------------|---------------|
| Thermal Resistance, Junction to Case<br>Case Temperature 80 $^{\circ}C$ , 150 W CW<br>Case Temperature 76 $^{\circ}C$ , 33 W CW | $R_{\theta JC}$ | 0.34<br>0.34 | $^{\circ}C/W$ |

**Table 3. ESD Protection Characteristics**

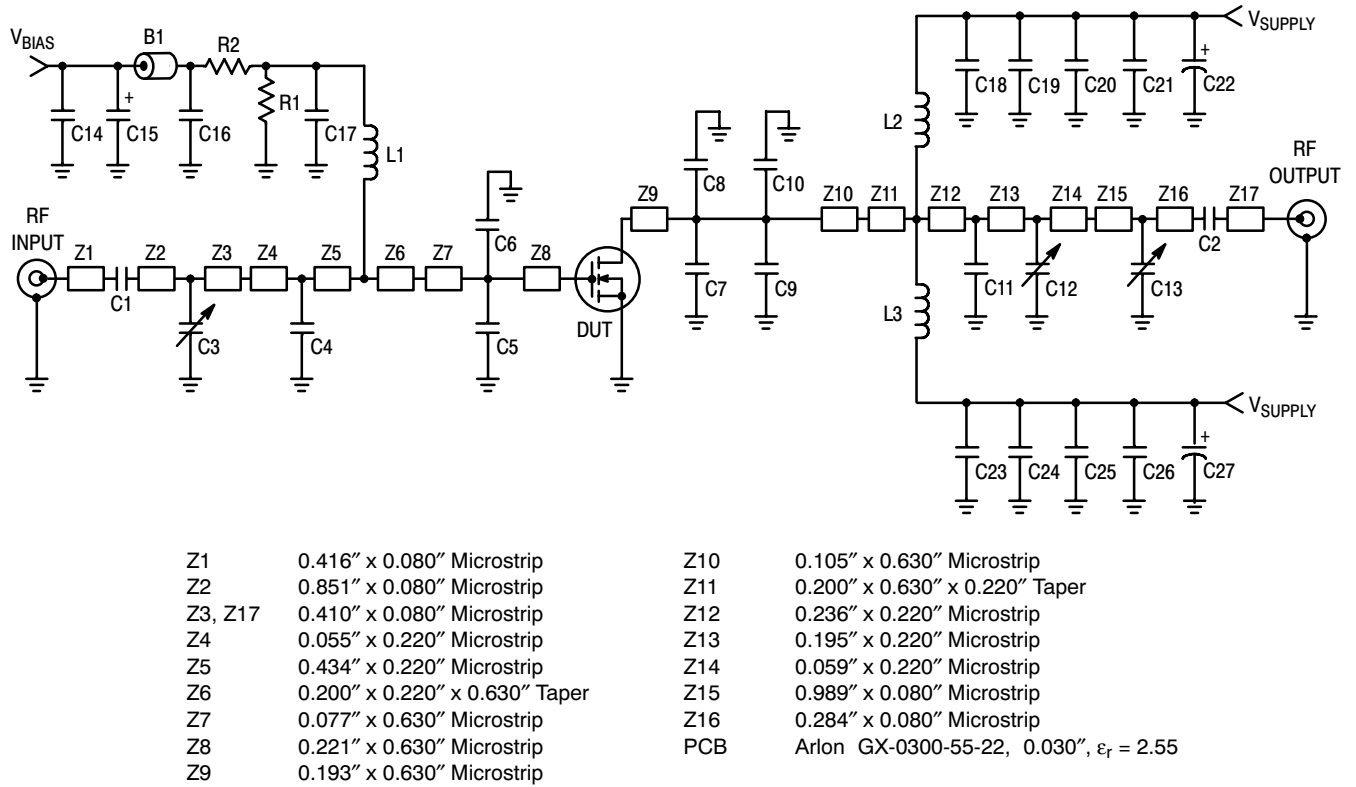
| Test Methodology                      | Class         |
|---------------------------------------|---------------|
| Human Body Model (per JESD22-A114)    | 1C (Minimum)  |
| Machine Model (per EIA/JESD22-A115)   | A (Minimum)   |
| Charge Device Model (per JESD22-C101) | III (Minimum) |

1. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>.  
Select Documentation/Application Notes - AN1955.

**Table 4. Electrical Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise noted)

| Characteristic  | Symbol       | Min  | Typ   | Max  | Unit            |
|---|--------------|------|-------|------|-----------------|
| <b>Off Characteristics</b>  |              |      |       |      |                 |
| Zero Gate Voltage Drain Leakage Current<br>( $V_{DS} = 68\text{ Vdc}$ , $V_{GS} = 0\text{ Vdc}$ )   | $I_{DSS}$    | —    | —     | 10   | $\mu\text{Adc}$ |
| Zero Gate Voltage Drain Leakage Current<br>( $V_{DS} = 28\text{ Vdc}$ , $V_{GS} = 0\text{ Vdc}$ )   | $I_{DSS}$    | —    | —     | 1    | $\mu\text{Adc}$ |
| Gate-Source Leakage Current<br>( $V_{GS} = 5\text{ Vdc}$ , $V_{DS} = 0\text{ Vdc}$ )  | $I_{GSS}$    | —    | —     | 500  | $\text{nAdc}$   |
| <b>On Characteristics</b>   |              |      |       |      |                 |
| Gate Threshold Voltage<br>( $V_{DS} = 10\text{ Vdc}$ , $I_D = 600\ \mu\text{Adc}$ )   | $V_{GS(th)}$ | 2    | 3     | 4    | Vdc             |
| Gate Quiescent Voltage<br>( $V_{DS} = 28\text{ Vdc}$ , $I_D = 1500\ \text{mAdc}$ , Measured in Functional Test)   | $V_{GS(Q)}$  | 3    | 4     | 5    | Vdc             |
| Drain-Source On-Voltage<br>( $V_{GS} = 10\text{ Vdc}$ , $I_D = 3.15\ \text{Adc}$ )  | $V_{DS(on)}$ | 0.1  | 0.2   | 0.3  | Vdc             |
| <b>Dynamic Characteristics</b> <sup>(1)</sup>   |              |      |       |      |                 |
| Reverse Transfer Capacitance<br>( $V_{DS} = 28\text{ Vdc} \pm 30\ \text{mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$ )  | $C_{rss}$    | —    | 3.1   | —    | pF              |
| Output Capacitance<br>( $V_{DS} = 28\text{ Vdc} \pm 30\ \text{mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$ )  | $C_{oss}$    | —    | 91.5  | —    | pF              |
| <b>Functional Tests</b> (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 28\text{ Vdc}$ , $I_{DQ} = 1500\ \text{mA}$ , $P_{out} = 33\ \text{W Avg.}$ N-CDMA, $f = 880\ \text{MHz}$ , Single-Carrier N-CDMA, 1.2288 MHz Channel Bandwidth Carrier. ACPR measured in 30 kHz Channel Bandwidth @ $\pm 750\ \text{kHz}$ Offset. PAR = 9.8 dB @ 0.01% Probability on CCDF. |              |      |       |      |                 |
| Power Gain  | $G_{ps}$     | 18.5 | 19.7  | 21.5 | dB              |
| Drain Efficiency  | $\eta_D$     | 26.5 | 28.4  | —    | %               |
| Adjacent Channel Power Ratio  | ACPR         | —    | -46.8 | -45  | dBc             |
| Input Return Loss   | IRL          | —    | -20   | -9   | dB              |

1. Part internally input matched.



**Figure 1. MRF5S9150HR3 Test Circuit Schematic**

**Table 5. MRF5S9150HR3 Test Circuit Component Designations and Values**

| Part                         | Description                               | Part Number        | Manufacturer     |
|------------------------------|---|--------------------|------------------|
| B1                           | Small Ferrite Bead                        | 2743019447         | Fair Rite        |
| C1, C2, C17                  | 47 pF Chip Capacitors                     | ATC100B470JT500XT  | ATC              |
| C3, C12                      | 0.8-8.0 pF Variable Capacitors, Gigatrim  | 27291SL            | Johanson         |
| C4                           | 13 pF Chip Capacitor                      | ATC100B130JT500XT  | ATC              |
| C5, C6                       | 15 pF Chip Capacitors                     | ATC100B150JT500XT  | ATC              |
| C7, C8                       | 12 pF Chip Capacitors                     | ATC100B120JT500XT  | ATC              |
| C9, C10                      | 4.3 pF Chip Capacitors                    | ATC100B4R3JT500XT  | ATC              |
| C11                          | 8.2 pF Chip Capacitor                     | ATC100B8R2JT500XT  | ATC              |
| C13                          | 0.6-4.5 pF Variable Capacitor, Gigatrim   | 27271SL            | Johanson         |
| C14                          | 22 pF Chip Capacitor                      | ATC100B220JT500XT  | ATC              |
| C15                          | 1 $\mu$ F, 50 V Tantalum Capacitor        | T491C105K050AT     | Kemet            |
| C16                          | 20K pF Chip Capacitor                     | CDR35BP203AKYM     | Kemet            |
| C18, C23                     | 180 pF Chip Capacitors                    | ATC100B181JT500XT  | ATC              |
| C19, C20, C21, C24, C25, C26 | 10 $\mu$ F, 50 V Chip Capacitors          | GRM55DR61H106KA88B | Murata           |
| C22, C27                     | 470 $\mu$ F, 63 V Electrolytic Capacitors | EMVY630GTR471MMH0S | Nippon Chemi-Con |
| L1, L2, L3                   | 12.5 nH Inductors                         | A04T               | Coilcraft        |
| R1                           | 180 k $\Omega$ , 1/4 W Chip Resistor      | CRCW12061803FKEA   | Vishay           |
| R2                           | 10 $\Omega$ , 1/4 W Chip Resistor         | CRCW120610R0FKEA   | Vishay           |

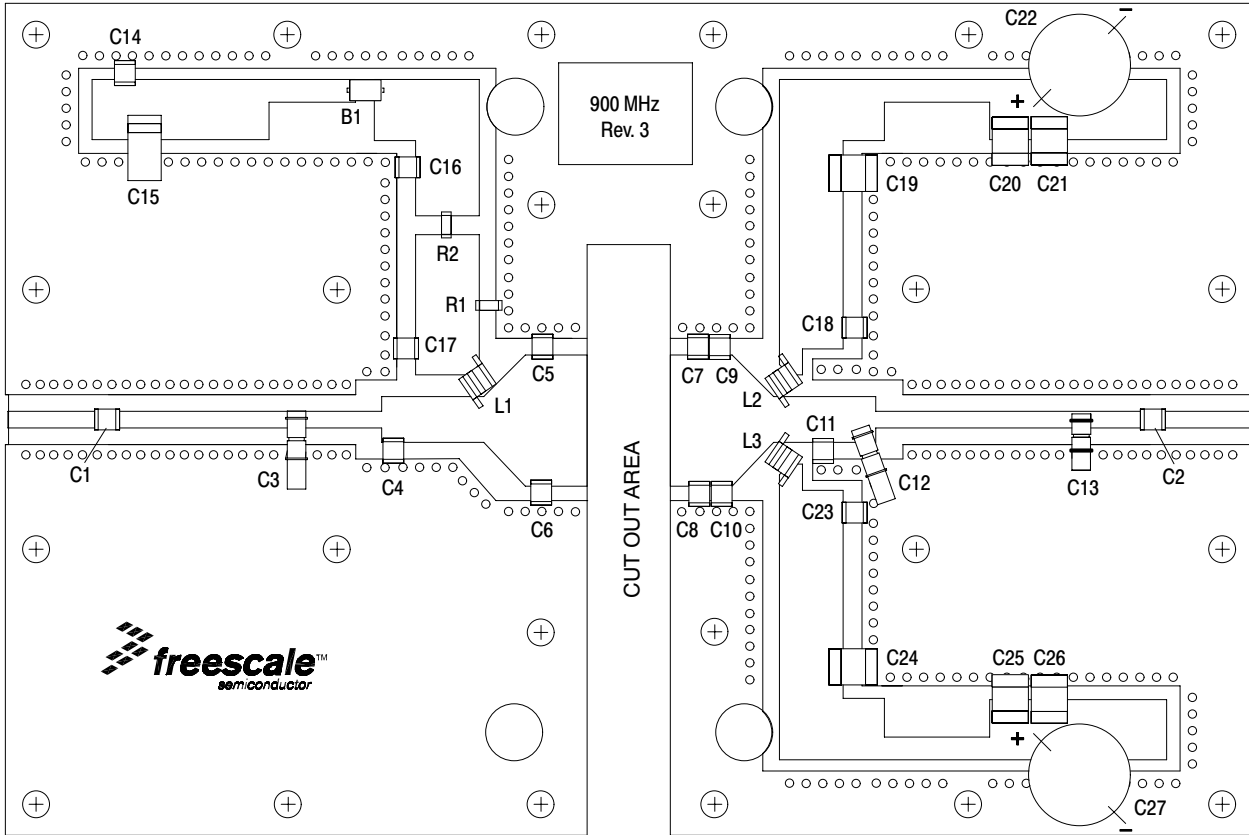


Figure 2. MRF5S9150HR3 Test Circuit Component Layout

## TYPICAL CHARACTERISTICS

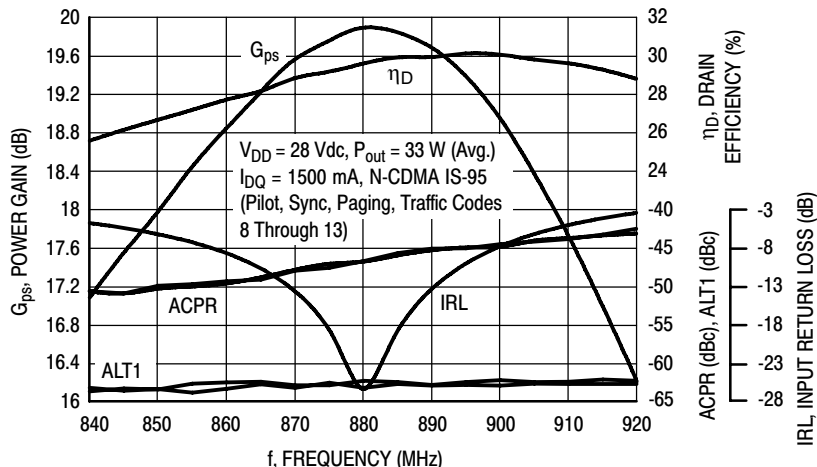


Figure 3. Single-Carrier N-CDMA Broadband Performance @  $P_{out} = 33$  Watts Avg.

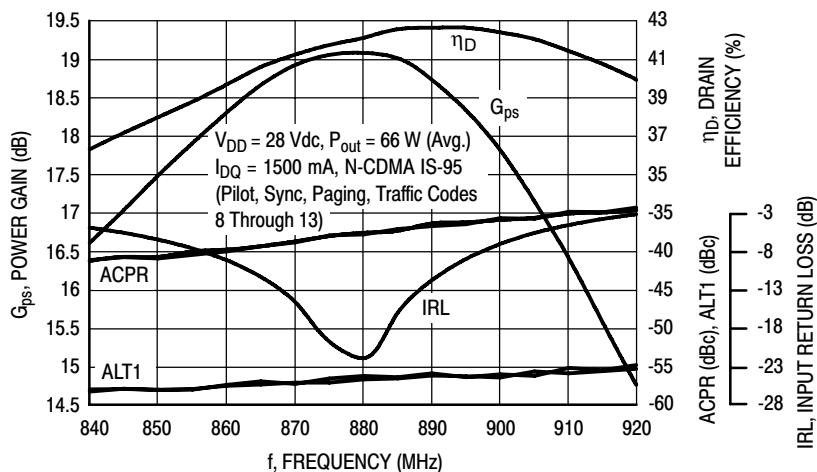


Figure 4. Single-Carrier N-CDMA Broadband Performance @  $P_{out} = 66$  Watts Avg.

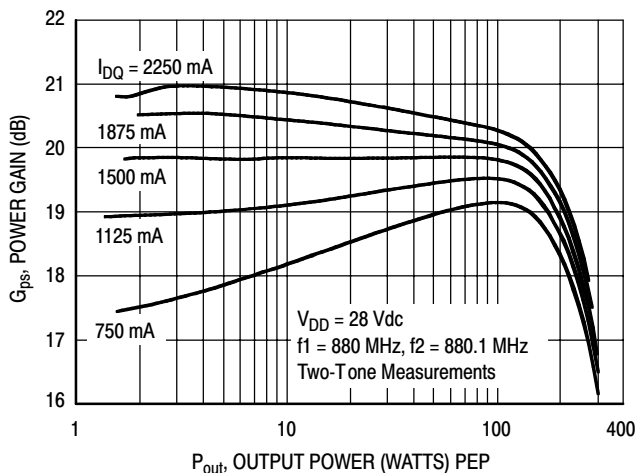


Figure 5. Two-Tone Power Gain versus Output Power

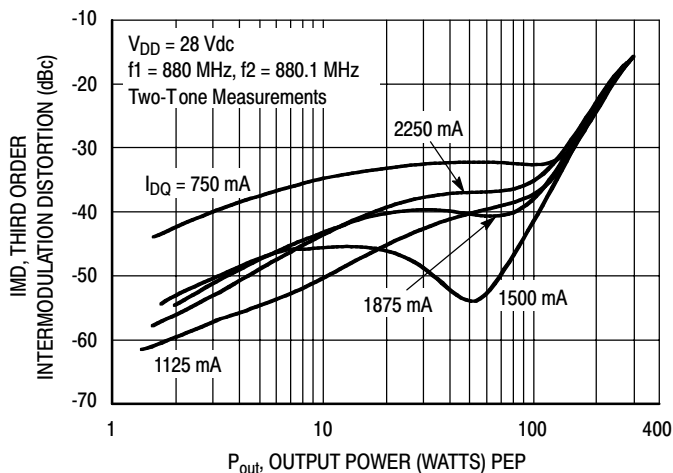
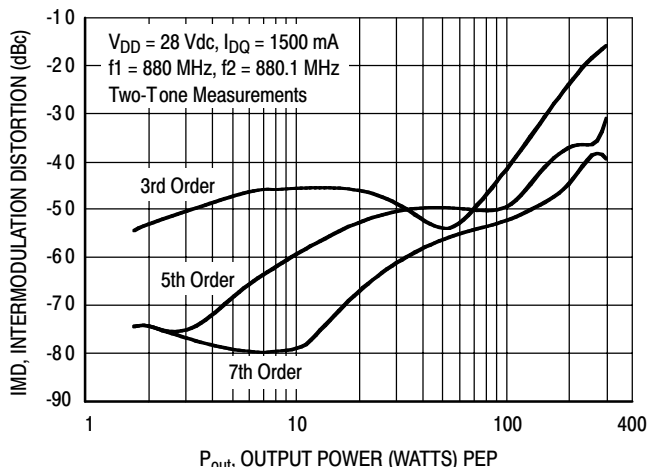
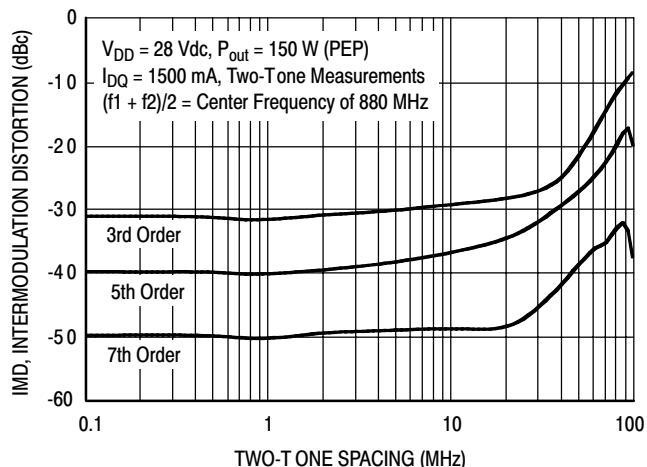


Figure 6. Third Order Intermodulation Distortion versus Output Power

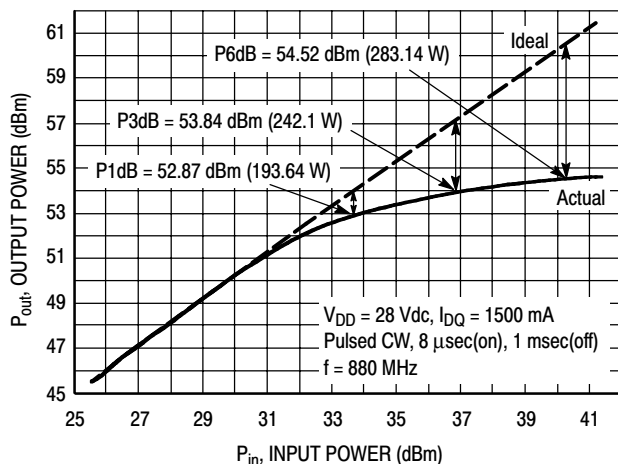
## TYPICAL CHARACTERISTICS



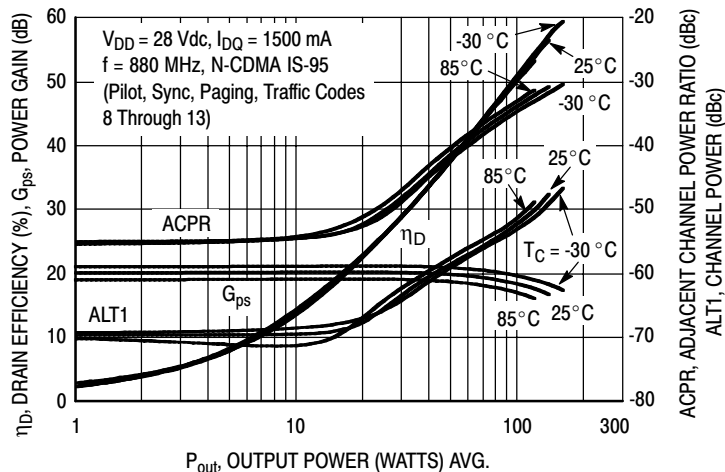
**Figure 7. Intermodulation Distortion Products versus Output Power**



**Figure 8. Intermodulation Distortion Products versus Tone Spacing**



**Figure 9. Pulse CW Output Power versus Input Power**



**Figure 10. Single-Carrier N-CDMA ACPR, ALT1, Power Gain and Drain Efficiency versus Output Power**

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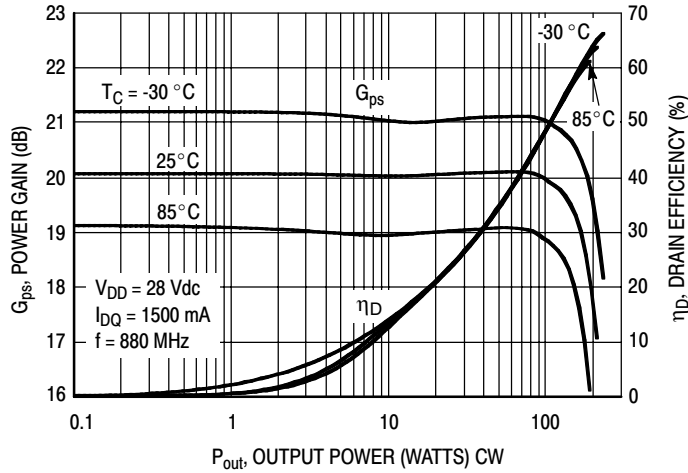


Figure 11. Power Gain and Drain Efficiency versus CW Output Power

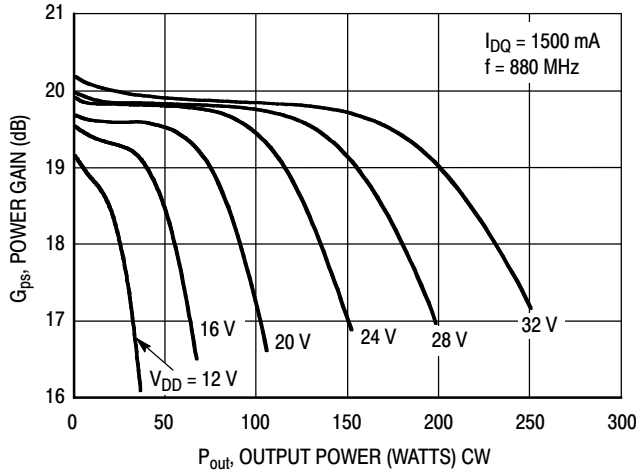
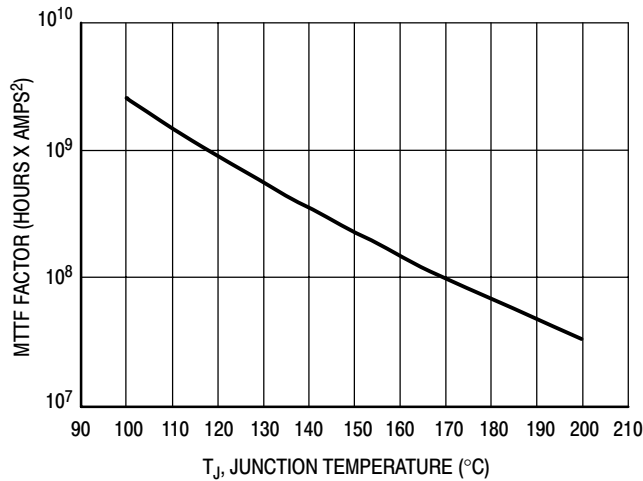


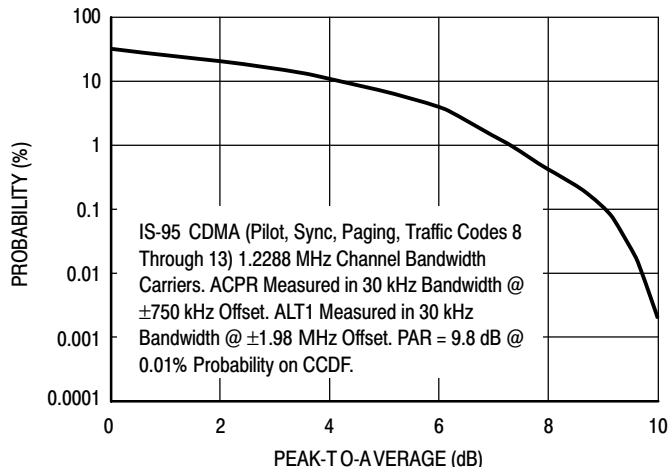
Figure 12. Power Gain versus Output Power



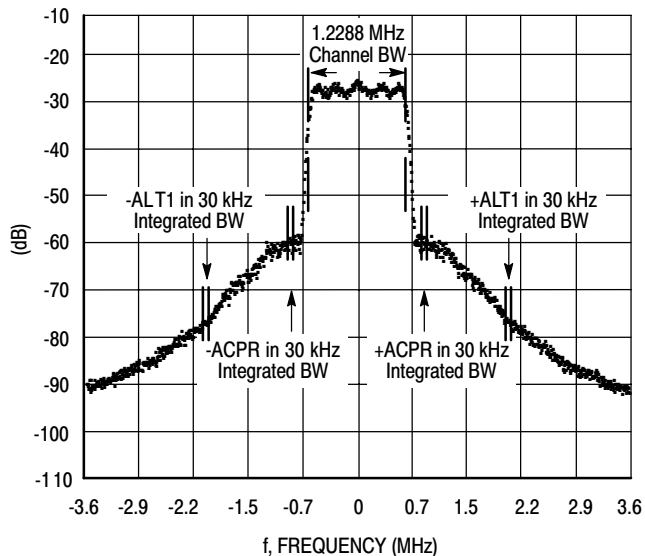
This above graph displays calculated MTTF in hours x ampere<sup>2</sup> drain current. Life tests at elevated temperatures have correlated to better than ±10% of the theoretical prediction for metal failure. Divide MTTF factor by I<sub>D</sub><sup>2</sup> for MTTF in a particular application.

Figure 13. MTTF Factor versus Junction Temperature

## N-CDMA TEST SIGNAL



**Figure 14. Single-Carrier CCDF N-CDMA**

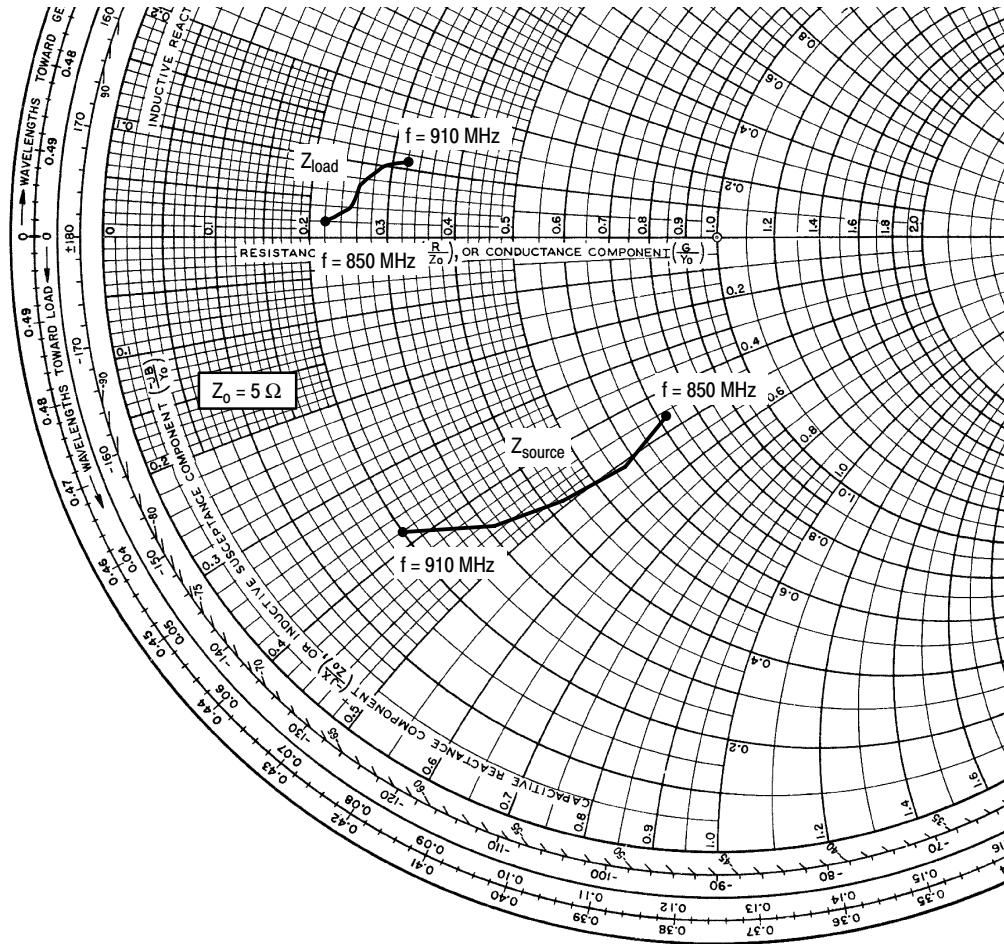


**Figure 15. Single-Carrier N-CDMA Spectrum**

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$V_{DD} = 28 \text{ Vdc}$ ,  $I_{DQ} = 1500 \text{ mA}$ ,  $P_{out} = 33 \text{ W Avg.}$

| f<br>MHz | $Z_{source}$<br>$\Omega$ | $Z_{load}$<br>$\Omega$ |
|----------|--------------------------|------------------------|
| 850      | $3.61 - j2.30$           | $1.12 + j0.09$         |
| 865      | $2.85 - j2.54$           | $1.24 + j0.22$         |
| 880      | $2.13 - j2.47$           | $1.31 + j0.36$         |
| 895      | $1.53 - j2.27$           | $1.46 + j0.48$         |
| 910      | $1.02 - j1.90$           | $1.61 + j0.53$         |

$Z_{source}$  = Test circuit impedance as measured from gate to ground.

$Z_{load}$  = Test circuit impedance as measured from drain to ground.

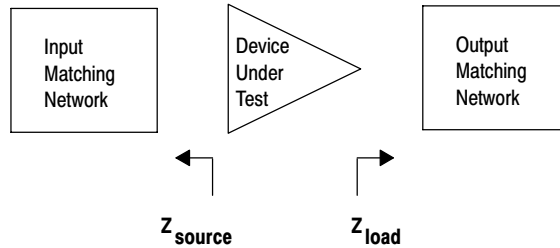
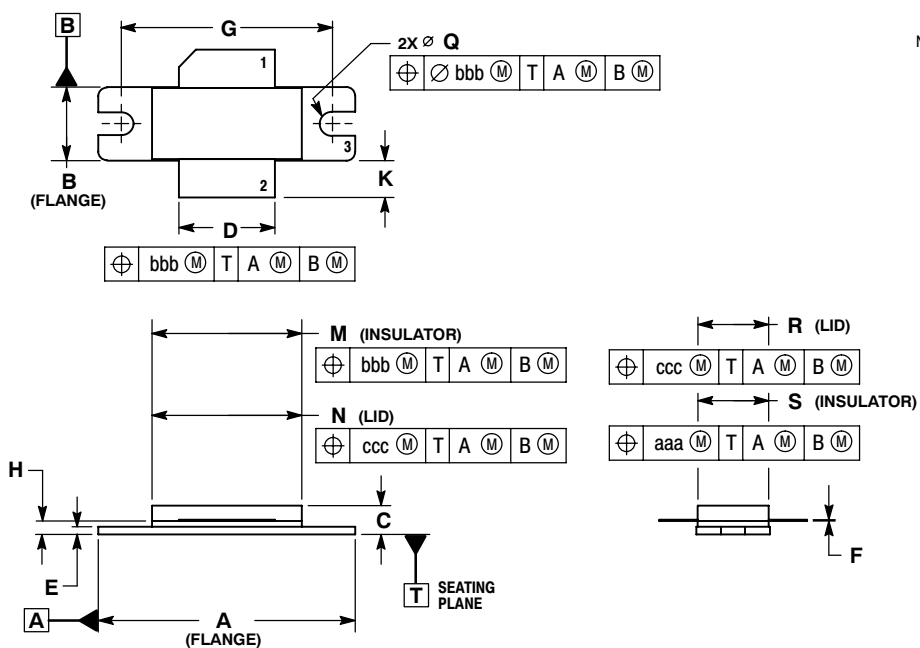


Figure 16. Series Equivalent Source and Load Impedance

## PACKAGE DIMENSIONS



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
  2. CONTROLLING DIMENSION: INCH.
  3. DELETED
  4. DIMENSION H IS MEASURED 0.030 (0.762) AWAY FROM PACKAGE BODY.

| DIM | INCHES    |       | MILLIMETERS |       |
|-----|-----------|-------|-------------|-------|
|     | MIN       | MAX   | MIN         | MAX   |
| A   | 1.335     | 1.345 | 33.91       | 34.16 |
| B   | 0.380     | 0.390 | 9.65        | 9.91  |
| C   | 0.125     | 0.170 | 3.18        | 4.32  |
| D   | 0.495     | 0.505 | 12.57       | 12.83 |
| E   | 0.035     | 0.045 | 0.89        | 1.14  |
| F   | 0.003     | 0.006 | 0.08        | 0.15  |
| G   | 1.100 BSC |       | 27.94 BSC   |       |
| H   | 0.057     | 0.067 | 1.45        | 1.70  |
| K   | 0.170     | 0.210 | 4.32        | 5.33  |
| M   | 0.774     | 0.786 | 19.66       | 19.96 |
| N   | 0.772     | 0.788 | 19.60       | 20.00 |
| Q   | ∅.118     | ∅.138 | ∅3.00       | ∅3.51 |
| R   | 0.365     | 0.375 | 9.27        | 9.53  |
| S   | 0.365     | 0.375 | 9.27        | 9.52  |
| aaa | 0.005 REF |       | 0.127 REF   |       |
| bbb | 0.010 REF |       | 0.254 REF   |       |
| ccc | 0.015 REF |       | 0.381 REF   |       |

- STYLE 1:  
 PIN 1. DRAIN  
 2. GATE  
 3. SOURCE

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## REVISION HISTORY

The following table summarizes revisions to this document.

| Revision | Date      | Description   |
|----------|-----------|---|
| 2        | Dec. 2009 | <ul style="list-style-type: none"><li>• Data sheet revised to reflect part status change, p. 1, 3-4, including use of applicable overlay.</li><li>• Data sheet archived. Part no longer manufactured. See MRF5S9150H-2 for MRF5S9150HS part.</li><li>• Updated Part Numbers in Table 5, Component Designations and Values, to RoHS compliant part numbers, p. 3</li><li>• Added Revision History, p. 11</li></ul> |

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